

# 600V High Voltage 3 Phase Bridge Driver

## BS2130F-G

#### **General Description**

The BS2130F is a monolithic bridge driver IC, which can drive N-channel power MOSFET and IGBT driver in 3 phase systems with bootstrap operations.

The floating channel can be used to driven an N-channel power MOSFET or IGBT in the high side configuration which operates up to 600V.

The logic inputs can be used 3.3V and 5.0V.

To provide a protection circuit, the device Includes an Under Voltage Lockout (UVLO) circuit and an Over Current Protection (OCP) circuit.

The UVLO circuit prevents malfunction when VCC and VBS are lower than the specified threshold voltage.

#### **Features**

- Floating Channels for Bootstrap Operation to +600V
- Gate drive supply range from 11.5V to 20V
- Built-in Under Voltage Lockout for Both Channels
- The device includes an Over Current Protection circuit
- Built-in Enable Channel (EN) which enable I/O functionality
- Built-in FAULT Channel (/FAULT) which indicates over current and under voltage
- RCIN Channel can determine the OCP holding time by external resistance and capacitance
- 3.3V and 5.0V input logic compatible
- Output in phase with input

#### **Applications**

■ MOSFET and IGBT high side driver applications

#### **Key Specifications**

High-side floating supply voltage: 600V Output voltage range: 11.5 ~ 20V Min Output Current lo+/lo-: 200mA/350mA(Typ) OCP detect voltage 0.46V(Typ) OCP blanking time 150ns(Typ) Turn On/Turn Off: 630/580ns(Typ) Offset supply leakage current: 50μA (Max) Operating temperature range: -40°C ~+125°C

**Package** W(Typ) x D(Typ) x H(Max) SOP-28 18.50mm x 9.90mm x 2.41mm





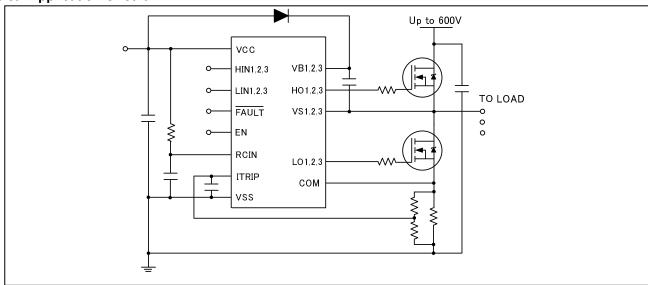


Figure 1. Typical Application Circuit

## **Pin Configuration**

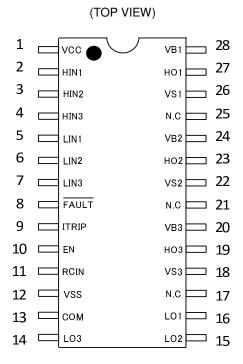


Figure 2. Pin Configuration

## **Pin Description**

Pin No.	Symbol	Function
1	VCC	Low side supply voltage
2,3,4	HIN1,2,3	Logic input for high side gate driver outputs (HO1,2,3), in phase
5,6,7	LIN1,2,3	Logic input for low side gate driver outputs (LO1,2,3), in phase
8	/FAULT	Indicates over current or low side undervoltage (negative logic, open-drain output)
9	ITRIP	Analog input for over-current shutdown, activates FAULT and RCIN to VSS
10	EN	Logic input to enable I/O functionality (positive logic)
11	RCIN	External RC-network to define FAULT clear delay after the t <sub>HOLD</sub>
12	VSS	Logic Ground
13	COM	Power Ground
14,15,16	LO1,2,3	Low side gate drive outputs
18,22,26	VS1,2,3,	High side floating supply return
19,23,27	HO1,2,3	High side gate drive outputs
20,24,28	VB1,2,3	High side floating supply
17,21,25	N.C	Non-Connection

## **Block Diagram**

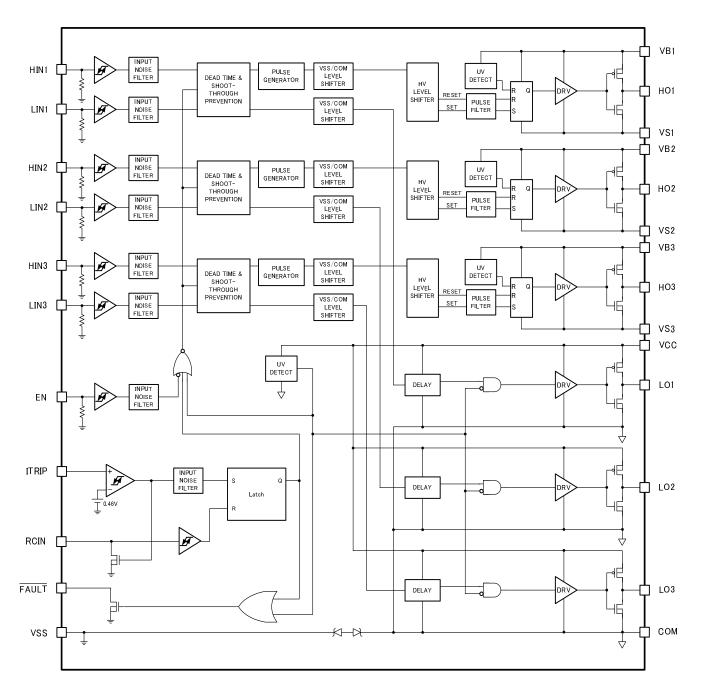


Figure 3. Functional Block Diagram

## **Absolute Maximum Ratings**

(Unless otherwise specified: All voltages are absolute voltages referenced to VSS. VSS=0V, Ta=25°C)

Parameter	Symbol	Min	Max	Unit
High side offset voltage	Vs	V <sub>B</sub> -25	V <sub>B</sub> +0.3	V
High side floating supply voltage	V <sub>B</sub>	V <sub>COM</sub> -0.3	V <sub>COM</sub> +625	V
High side floating output voltage HO	V <sub>HO</sub>	V <sub>S</sub> -0.3	V <sub>B</sub> +0.3	V
Low side and logic fixed supply voltage (VCC vs. VSS)	Vcc	-0.3	+25	V
Low side and logic fixed supply voltage (VCC vs. COM)	V <sub>CCCOM</sub>	-0.3	+25	V
Low side output voltage LO (LO vs. COM)	$V_{LO}$	-0.3	V <sub>CCCOM</sub> +0.3	V
Logic input voltage HIN, LIN, EN	V <sub>IN</sub>	-0.3	V <sub>CC</sub> +0.3	V
FAULT output voltage	$V_{FLT}$	-0.3	V <sub>CC</sub> +0.3	V
RCIN input voltage	V <sub>RCIN</sub>	-0.3	V <sub>CC</sub> +0.3	V
ITRIP input voltage	V <sub>ITRIP</sub>	-0.3	V <sub>CC</sub> +0.3	V
Power ground	V <sub>COM</sub>	-5.5	+5.5	V
Allowable offset voltage SLEW RATE	dV <sub>S</sub> /dt	-	50	V/ns
Junction temperature	Tjmax	-	150	°C
Storage temperature	Tstg	-55	+150	°C

## Thermal Resistance (Note 1)

Developator	Courselle al	Thermal Res	Unit	
Parameter   Parame	Symbol	1s <sup>(Note 3)</sup>	1s <sup>(Note 3)</sup> 2s2p <sup>(Note 4)</sup>	
SOP28	·			
Junction to Ambient	$\theta_{JA}$	136.9	88.6	°C/W
Junction to Top Characterization Parameter <sup>(Note 2)</sup>	$\Psi_{ m JT}$	19	15	°C/W

(Note 1)Based on JESD51-2A(Still-Air)
(Note 2)The thermal characterization parameter to report the difference between junction temperature and the temperature at the top center of the outside surface of the component package.

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(Note 3)Using a	PCB board	l based on JESD5	1-3.

(Note 3)Using a PCB board based		
Layer Number of Measurement Board	Material	Board Size
Single	FR-4	114.3mm x 76.2mm x 1.57mmt
Тор		
Copper Pattern	Thickness	
Footprints and Traces	70um	

(Note 4)Using a PCB board based on JESD51-7.

Layer Number of Measurement Board	Material	Board Size
4 Layers	FR-4	114.3mm x 76.2mm x 1.6mmt

Тор		2 Internal Laye	ers	Bottom		
Copper Pattern	Thickness	Copper Pattern Thickness		Copper Pattern	Thickness	
Footprints and Traces	70µm	74.2mm x 74.2mm	35µm	74.2mm x 74.2mm	70µm	

## **Recommended Operating Ratings**

(Unless otherwise specified: All voltages are absolute voltages referenced to VSS. VSS=0V)

Parameter	Symbol	Min	Max	Unit
High side floating supply offset voltage (VS vs. COM)	Vs	-	600	٧
High side floating supply voltage (VB vs. VS)	V <sub>B</sub>	11.5	20	٧
High side floating output voltage (HO vs. VS)	V <sub>HO</sub>	0	V <sub>B</sub>	٧
Low side supply voltage (VCC vs. VSS)	Vcc	11.5	20	٧
Low side supply voltage (VCC vs. COM)	V <sub>CCCOM</sub>	11.5	20	٧
Low side output voltage LO (LO vs. COM)	V <sub>LO</sub>	0	V <sub>CCCOM</sub>	٧
Logic input voltage HIN, LIN, EN	V <sub>IN</sub>	0	V <sub>CC</sub>	٧
FAULT output voltage	V <sub>FLT</sub>	0	V <sub>CC</sub>	٧
RCIN input voltage	V <sub>RCIN</sub>	0	V <sub>CC</sub>	٧
ITRIP input voltage	V <sub>ITRIP</sub>	0	V <sub>CC</sub>	V
Power ground	V <sub>СОМ</sub>	-2.5	+2.5	V
Ambient temperature	T <sub>A</sub>	-40	+125	°C

## **Static Logic Function Table**

vcc	VBS	RCIN	ITRIP	EN	FAULT	HO1,2,3	LO1,2,3
<vccuv-< td=""><td>Х</td><td>Х</td><td>X</td><td>Х</td><td>0</td><td>0</td><td>0</td></vccuv-<>	Х	Х	X	Х	0	0	0
15V	<vbsuv-< td=""><td>Х</td><td>0V</td><td>5V</td><td>High-Z</td><td>0</td><td>LIN1,2,3</td></vbsuv-<>	Х	0V	5V	High-Z	0	LIN1,2,3
15V	15V	Х	>V <sub>IT,TH+</sub>	5V	0	0	0
15V	15V	<v<sub>RCIN+</v<sub>	0V	5V	0 <sup>(Note 1)</sup>	0 <sup>(Note 1)</sup>	0 <sup>(Note 1)</sup>
15V	15V	>V <sub>RCIN+</sub>	0V	5V	High-Z	HIN1,2,3	LIN1,2,3
15V	15V	>V <sub>RCIN+</sub>	0V	0V	High-Z	0	0

(Note 1) State after the OCP. Because the latch circuit is not reset, the OCP state is maintained.

## **DC Operation Electrical Characteristics**

(Unless otherwise specified: Ta=25°C,  $V_{CC}$ =15V,  $V_{BS}$ =15V,  $V_{S}$ = $V_{SS}$ = $V_{COM}$ ,  $C_L$ =1000pF)

Davaractor	Curahal		Limits		Unit	Conditions	
Parameter	Symbol	Min	Тур	Max	Uffil	Conditions	
$V_{\text{CC}}$ and $V_{\text{BS}}$ supply undervoltage positive going threshold	$V_{\text{CCUV+}}$ $V_{\text{BSUV+}}$	9.6	10.4	11.2			
$V_{\text{CC}}$ and $V_{\text{BS}}$ supply undervoltage negative going threshold	V <sub>CCUV-</sub> V <sub>BSUV-</sub>	8.6	9.4	10.2	V		
V <sub>CC</sub> supply undervoltage lockout hysteresis	$V_{\text{CCUVH}}$ $V_{\text{BSUVH}}$	-	1.0	-			
Offset supply leakage current	I <sub>LK</sub>	-	-	50		$V_B = V_S = 600V$	
Quiescent V <sub>BS</sub> supply current	$I_{QBS}$	-	60	120	μΑ	V <sub>IN</sub> = 0V or 5V	
Quiescent V <sub>CC</sub> supply current	Iacc	-	0.7	1.3	mA	V <sub>IN</sub> = 0V or 5V	
Logic "1" input voltage	V <sub>IH</sub>	2.6	-	-			
Logic "0" input voltage	V <sub>IL</sub>	-	-	0.8	V		
EN positive going threshold	$V_{\text{EN+}}$	-	-	2.6	V		
EN negative going threshold	V <sub>EN-</sub>	0.8	-	-			
RCIN positive going threshold	$V_{RCIN_{+}}$	-	8	-	V		
RCIN hysteresis	V <sub>RCIN,HYS</sub>	-	3	-	V		
ITRIP positive going threshold	$V_{\text{IT,TH+}}$	0.437	0.46	0.483	V		
ITRIP hysteresis	V <sub>IT,HYS</sub>	-	0.07	-	V		
High level output voltage, $V_{\text{CC}}(V_{\text{BS}})$ - $V_{\text{O}}$	V <sub>OH</sub>	-	-	1.4	V	I <sub>O</sub> = 20mA	
Low level output voltage, V <sub>O</sub>	V <sub>OL</sub>	-	-	0.6	V	10 = 2011IA	
Logic "1" input bias current	I <sub>IN+</sub>	-	100	150		V <sub>IN</sub> = 3.3V	
Logic "0" input bias current	I <sub>IN-</sub>	-	-	1.0	μΑ	V <sub>IN</sub> = 0V	
ITRIP input bias current	I <sub>ITRIP</sub>	-	1	2		V <sub>ITRIP</sub> = 0V or 3.3V	
Output high short circuit pulse current	I <sub>O+</sub>	120	200	-	m- A	$V_0 = 0V$ Pulse Width $\leq 10\mu s$	
Output low short circuit pulsed current	I <sub>O-</sub>	250	350	-	mA	V <sub>O</sub> = 15V Pulse Width ≦10μs	
RCIN input bias current	I <sub>RCIN</sub>	-	-	1	μΑ		
RCIN low on resistance	R <sub>ON_RCIN</sub>	-	50	100		V <sub>RCIN</sub> = 0.5V	
FAULT low on resistance	R <sub>ON_FAULT</sub>	-	50	100	Ω	V <sub>FAULT</sub> = 0.5V	

## **AC Operation Electrical Characteristics**

Parameter	Symbol		Limits		Unit	Conditions
Farameter	Symbol	Min	Тур	Max	UTIIL	Conditions
Turn-on propagation delay	t <sub>on</sub>	480	630	780		$V_S = 0V, V_{IN} = 0V \& 5V$
Turn-off propagation delay	t <sub>off</sub>	430	580	730		V <sub>S</sub> = 0V or 600V, V <sub>IN</sub> =0V&5V
Turn-on rise time	t <sub>r</sub>	-	125	190		V <sub>IN</sub> = 0V & 5V
Turn-off fall time	t <sub>f</sub>	-	50	75		V <sub>IN</sub> = 0V & 5V
EN low to output shutdown propagation delay	t <sub>EN</sub>	430	580	730		V <sub>IN</sub> ,V <sub>IN</sub> = 0V & 5V
ITRIP to output shutdown propagation delay	t <sub>ITRIP</sub>	500	750	1000		V <sub>ITRIP</sub> = 5V
ITRIP blanking time	t <sub>bl</sub>	100	150	-	ns	V <sub>ITRIP</sub> = 5V
ITRIP to FAULT propagation delay	t <sub>FLT</sub>	400	600	800		V <sub>ITRIP</sub> = 5V
Input filter time (HIN,LIN)	t <sub>FILIN</sub>	100	200	-		V <sub>IN</sub> = 0V & 5V
Enable input filter time	t <sub>FLTEN</sub>	100	200	-		V <sub>IN</sub> = 0V & 5V
Dead time	DT	250	300	450		V <sub>IN</sub> = 0V & 5V
Delay matching, HS & LS turn-on/off	MT	-	-	150		
FAULT clear time	t <sub>FLTCLR</sub>	1.3	1.65	2.0	ms	RCIN : $R = 2M\Omega$ , $C = 1nF$

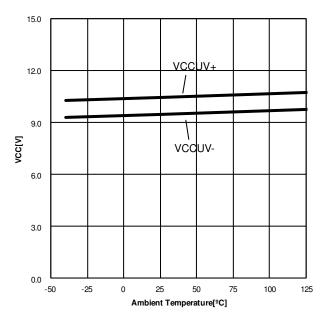


Figure 4. V<sub>CC</sub> UVLO - Ta

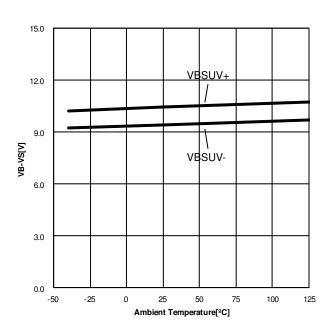


Figure 5. V<sub>BS</sub> UVLO - Ta

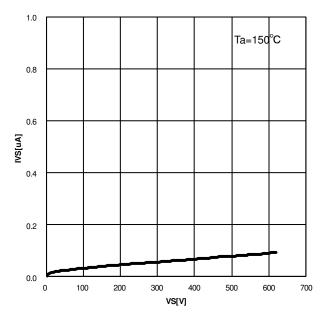


Figure 6. Offset supply leakage current -  $V_{\text{S}}$  $(V_B=V_S)$ 

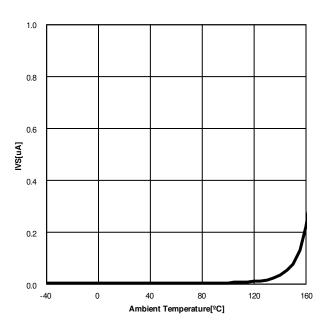
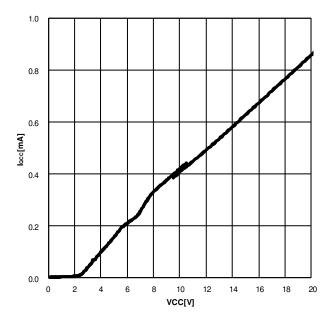


Figure 7. Offset supply leakage current - Ta  $(V_B = V_S = 600V)$ 



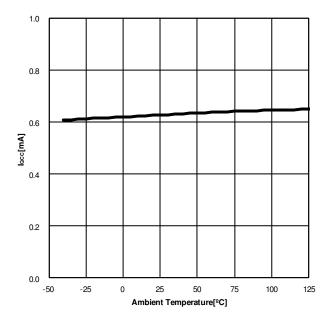


Figure 8. Quiescent  $V_{\text{CC}}$  supply current -  $V_{\text{CC}}$ 

Figure 9. Quiescent  $V_{CC}$  supply current – Ta  $(V_{CC}=15V)$ 

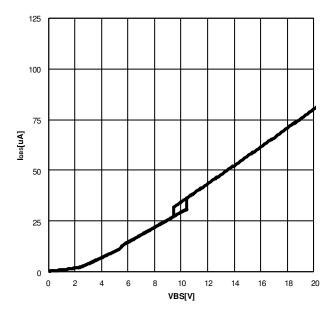


Figure 10. Quiescent  $V_{\text{BS}}$  supply current -  $V_{\text{BS}}$ 

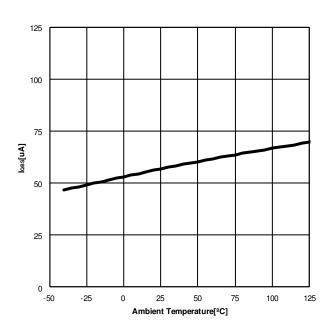


Figure 11. Quiescent  $V_{BS}$  supply current – Ta  $(V_{BS}=15V)$ 

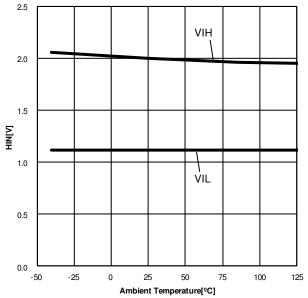


Figure 12. Logic "1"/"0" Input Voltage HIN - Ta

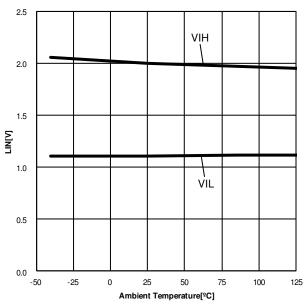


Figure 13. Logic "1"/"0" Input Voltage LIN - Ta

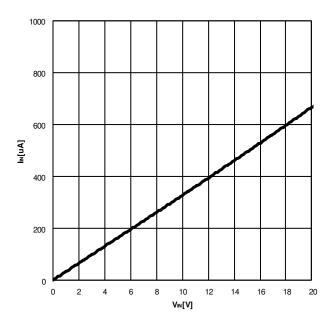


Figure 14. Logic "1" Input bias current - VIN

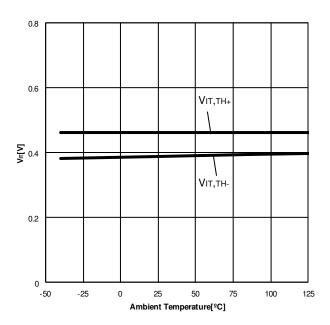


Figure 15. ITRIP threshold Voltage - Ta

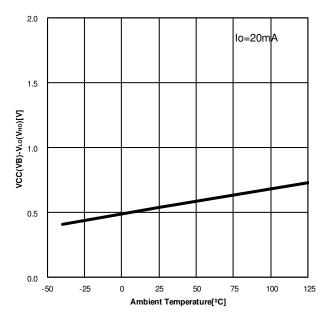


Figure 16. High Level Output Voltage - Ta

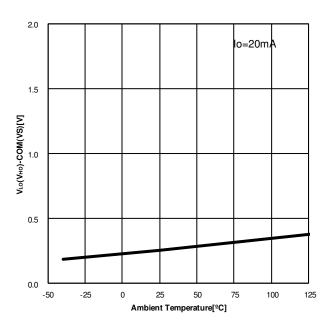


Figure 17. Low Level Output Voltage - Ta

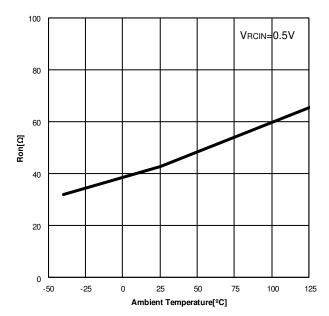


Figure 18. RCIN low on Resistance - Ta

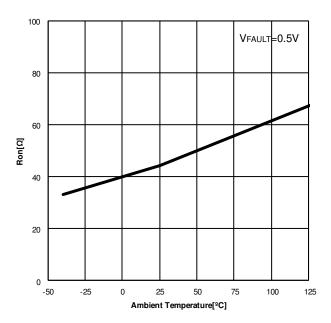


Figure 19. FAULT low on Resistance - Ta

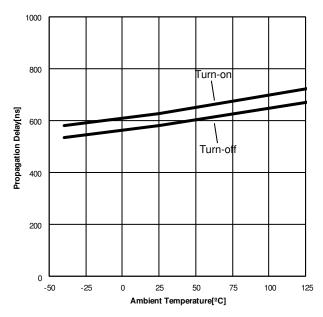


Figure 20. HO Turn on/off Propagation Delay - Ta

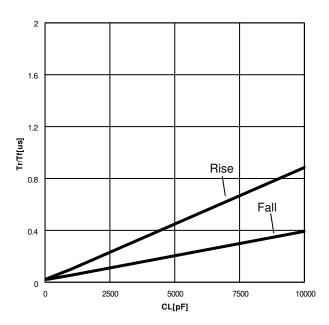


Figure 21. HO Rise/Fall Time - Load Capacitance

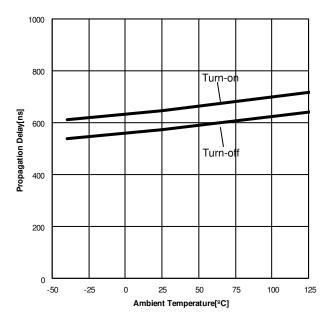


Figure 22. LO Turn on/off Propagation Delay - Ta

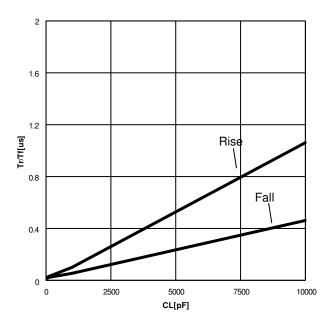


Figure 23. LO Rise/Fall Time - Load Capacitance

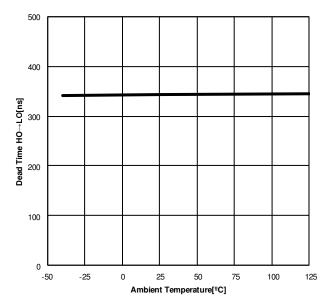


Figure 24. Dead time - Ta (HO off - LO on)

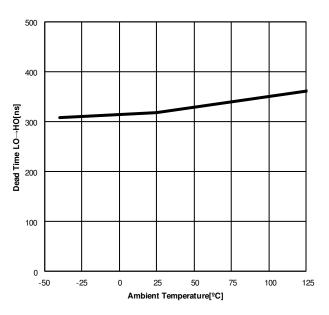


Figure 25. Dead time - Ta (LO off - HO on)

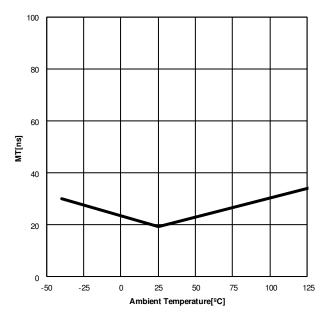


Figure 26. Delay matching Turn on/off - Ta

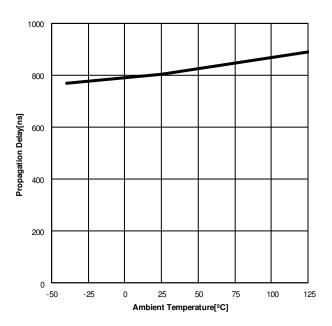
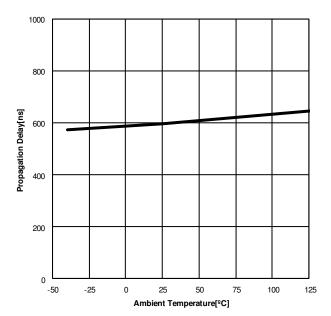


Figure 27. ITRIP to Output Shutdown Propagation Delay - Ta



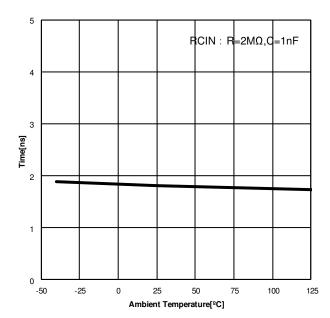
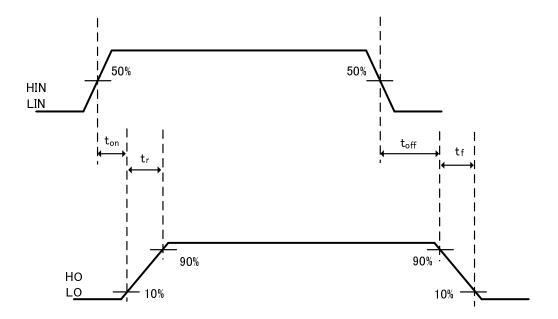


Figure 28. ITRIP to FAULT Propagation Delay - Ta

Figure 29. FAULT clear time - Ta

## **Timing Chart**



(a) Propagation Delay

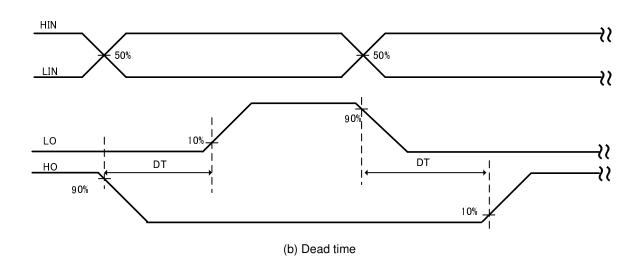


Figure 30. Timing Chart

## **Timing Chart**

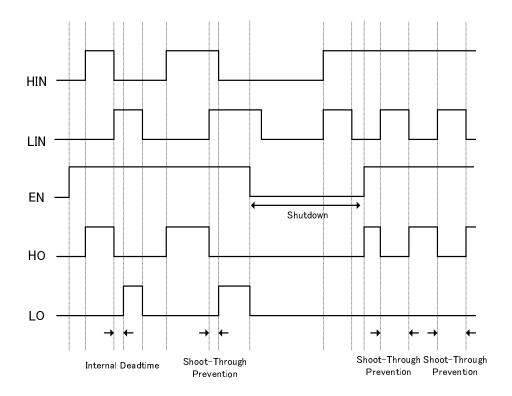


Figure 31. Timing Chart

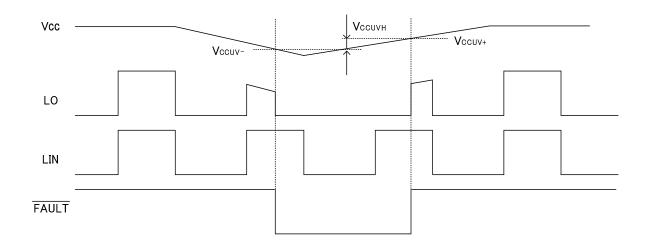


Figure 32. VCCUVLO Timing Chart

#### **Over Current Protection**

As soon as ITRIP voltage is exceeded the threshold voltage 0.46V (typ), impedance of the /FAULT pin is lowered and the RCIN pin turns off.

ITRIP blanking time 150ns (typ) prevents the driver to detect false over-current events which caused by noise. However, it is recommended to add a ceramic capacitor near the ITRIP pin.

FAULT clear time is determined by external resistance and capacitance. As soon as RCIN voltage exceeds the rising threshold voltage 8V (typ), the FAULT condition releases. Also, RCIN voltage operates in the voltage less than  $V_{RCIN+}$ . However, it is not returned with stopping when ITRIP voltage goes over threshold voltage  $V_{IT,TH+}$  once. RCIN voltage to recommend at the normal operation is more than  $V_{RCIN+}$ .

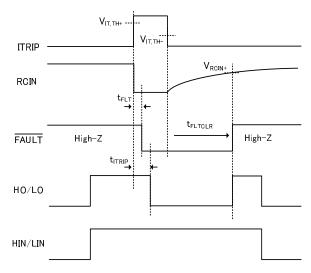


Figure 33. OCP Detection Timing Chart

The over current detection value is determined by R1, R2, and RS, which are connected to ITRIP pin as Figure 34. The over current detection value is determined by the following equation.

$$locp = \frac{R_1 + R_2}{R_2} \times \frac{V_{IT,TH+}}{R_S}$$

locp : over current detection value

V<sub>IT,TH+</sub>: OCP threshold voltage 0.46V(typ)

Rs : Shunt resistor

The reset time of FAULT is determined by the following equation.

$$t_{\text{FLTCLR}} = -(R_{\text{RCIN}} \times C_{\text{RCIN}}) \times ln(1 - \frac{V_{\text{RCIN}, \text{TH+}}}{V_{\text{CC}}})$$

V<sub>RCIN+</sub>: RCIN threshold voltage 8V(typ)

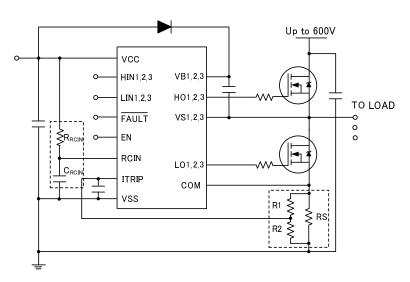


Figure 34. OCP Detection Schematic

#### **Application Components Selection Method**

#### (1) Gate Resistor

The gate resistor  $R_{\text{G(on/off)}}$  is selected to control the switching speed of the output transistor. The switching time  $(t_{\text{SW}})$  is defined as the time spent to reach the end of the plateau voltage, so the turn on gate resistor  $R_{\text{G(on)}}$  can be calculated using the following formulas.

$$I_g = \frac{Q_{gs} + Q_{gd}}{t_{SW}} \tag{1}$$

$$R_{TOTAL(on)} = R_{pon} + R_{G(on)} = \frac{V_{BS} - V_{gs(th)}}{I_{o}}$$
 (2)

$$t_{sw} = \frac{Q_{gs} + Q_{gd}}{I_g} = \frac{(Q_{gs} + Q_{gd})(R_{pon} + R_{G(on)})}{(V_{BS} - V_{gs(th)})}$$
(3)

Turn on gate resistor value can be changed to control output slope (dVs/dt). While the output voltage is non-linear, the maximum output slope should have a value near that of the following formula:

$$\frac{dVs}{dt} = \frac{I_g}{C_{rss}} \tag{4}$$

#### where:

C<sub>rss</sub> is the feedback capacitance.

Substituting the value of  $I_g$  from equation (2) into equation (4) yields the following formulas.

$$R_{TOTAL(on)} = R_{pon} + R_{G(on)} = \frac{V_{BS} - V_{gs(th)}}{C_{rss} \cdot \frac{dVs}{dt}}$$
(5)

$$R_{G(on)} = \frac{V_{BS} - V_{gs(th)}}{C_{rss} \cdot \frac{dVs}{dt}} - R_{pon}$$
 (6)

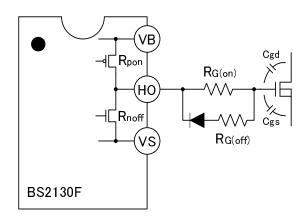


Figure 35. Gate Driver Equivalent Circuit

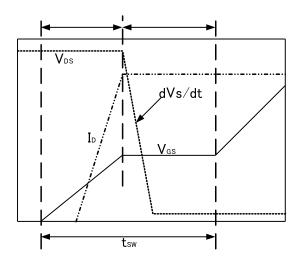


Figure 36. Gate Charge Transfer Characteristics

When the gate driver output is in off state, other dVs/dt may induce a drop in the gate voltage of the MOSFET, causing self-turn-on. To prevent this, please set up the turn off resistor ( $R_{G(off)}$ ) that satisfies the following formulas.

$$V_{gs(th)} \ge (R_{noff} + R_{G(off)}) \cdot I_g = (R_{noff} + R_{G(off)}) \cdot C_{gd} \frac{dVs}{dt}$$
(7)

$$R_{G(\text{off})} \le \frac{V_{gs(\text{th})}}{C_{gd}} - R_{\text{noff}}$$
(8)

#### (2) Bootstrap Capacitor CBS

To reduce ripple voltage, ceramic capacitors with low ESR value are recommended for use in the bootstrap circuit. The maximum voltage drop ( $\Delta V_{BS}$ ) that we have to guarantee when the high-side switch is in on state must be:

$$\Delta V_{BS} \le VCC - VF - V_{GSMIN} \tag{9}$$

#### where:

VCC is the gate driver supply voltage,

VF is the bootstrap diode forward voltage drop, and

V<sub>GSMIN</sub> is the minimum gate-source voltage.

The total charge supplied (Q<sub>Total</sub>) by the bootstrap capacitor should have a value near the following formulas.

$$Q_{Total} = Q_G + (I_{LKGS} + I_{LK} + I_{LKDIO} + I_{OBS}) \cdot T_{HON}$$
 (10)

#### where:

Q<sub>G</sub> is the total gate charge,

I<sub>LKGS</sub> is the switch gate-source leakage current,

I<sub>LKDIO</sub> is the bootstrap diode leakage current,

ILK is the level shifter circuit leakage current,

I<sub>QBS</sub> is the quiescent current, and

T<sub>HON</sub> is the high-side switch on time.

The bootstrap capacitor value should satisfy the following formula.

$$C_{BS} \ge \frac{Q_{Total}}{\Delta V_{RS}} \tag{11}$$

However, BS2130F has a BSTUVLO function to prevent malfunction at low voltage between VB and VS.

Please ensure sufficient capacitor margin to prevent BSTUVLO malfunction.

It is not able to keep turning-on the same way as the high side switch driver because of the specifications of the bootstrap circuits.

In addition, it is recommended to insert a 1 µF ceramic capacitor between VB and VS. This capacitor should be placed as close as possible to these pins for noise reduction.

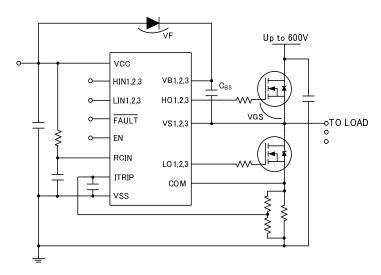


Figure 37. Bootstrap Power Supply Circuit

#### (3) Input Capacitor

Mount a low-ESR ceramic input capacitor near the VCC pin to reduce input ripple.

For BS2130F, it is recommended to use a capacitor value two times larger than that of the bootstrap capacitor or more.

#### (4) Input Signals Differential Δt<sub>IN</sub>

The minimum differential of input signals  $(\Delta t_{\text{IN(min)}})$  to prevent shoot-through of the MOSFETs can be calculated using the following formula.

$$t_{dead} \approx (t_{on} + \Delta t_{IN}) - (t_{off} + t_f) \tag{12}$$

$$t_f = -\tau \times (\ln 0.1 - \ln 0.9)$$
 (13)

$$\tau = (R_{non} + R_G) \times C_L \tag{14}$$

 $t_{\text{on}}$  : Turn-on propagation delay  $t_{\text{off}}$  : Turn-off propagation delay

t<sub>f</sub>: Turn-off fall time

R<sub>non</sub>: On-resistance of Nch MOSFET constituting the final stage inverter

 $R_G$ : Gate resistor  $C_L$ : Load capacitor

Please set up  $\Delta t_{\text{IN}}$  that satisfies the following formulas.

$$t_{dead} > 0 \tag{15}$$

$$(t_{on} + \Delta t_{IN}) - (t_{off} + t_f) > 0$$
 (16)

$$\Delta t_{IN} > (t_{off} - t_{ON}) + t_f \tag{17}$$

$$\Delta t_{IN(\text{min})} > (t_{off(\text{max})} - t_{on(\text{min})}) - (R_{non(\text{max})} + R_G) \times C_L \times (\ln 0.1 - \ln 0.9)$$
(18)

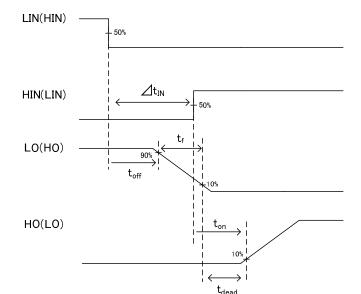


Figure 38. Shoot-Through Prevention Timing Chart

#### **Overshoot / Undershoot of Output Terminal**

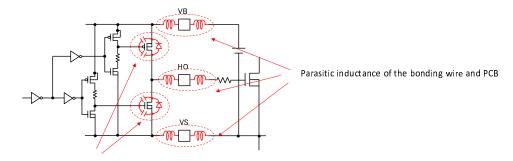
The occurrence of overshoot / undershoot may be detected by the parasitic inductance of the bonding wire and the PCB. The mechanism of overshoot in the switching off is Figure 40.

- (1) After PchFET is turn-off, current flows from HO to VB through capacitance between G-D and G-S.
- (2) The current flows from HO to VB through parasitic diode of PchFET. Forward voltage Vf of the parasitic diode is increased, and HO voltage becomes VB+Vf. NchFET is turn-on and it is discharged to VS.

The undershoot of the switching on may be caused by the same mechanism, too.

In addition, it may be caused in low side output LO because the circuit structure is the same. The overshoot / undershoot voltage changes by the current of the parasitic diode.

When the overshoot / undershoot voltage is large, please adjust the gate resistance to slow in order to the switching speed and connect to reduce the parasitic inductance.



Parasitic diode and capasitance between G-S and G-D

Figure 39. Schematic with Parasitic Inductance

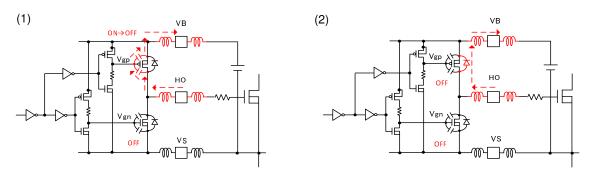


Figure 40. Mechanism of Overshoot

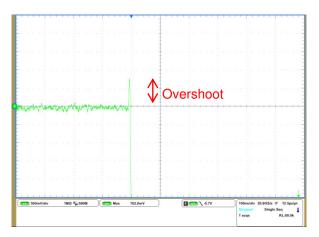


Figure 41. Overshoot Wave

#### **Power Dissipation**

It is shown below reducing characteristics of power dissipation to mount  $114.3 \text{mm} \times 76.2 \text{mm}$ . Junction temperature must be designed not to exceed  $150 \,^{\circ}\text{C}$ .

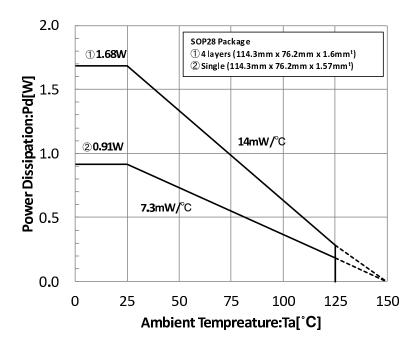


Figure 42. Power Dissipation

#### **PCB Layout**

## 1. Power GND and Logic GND

Surge voltage is caused by current of Power GND and parasitic inductance of the wire. It may cause malfunction by GND fluctuation. It is recommended to connect Power GND and Logic GND at only a point.

#### 2. Shunt Resistor

It is recommended to locate a shunt resistor near the external power MOSFET of low side. If the wiring is long, surge voltage is caused by parasitic inductance. The wiring to the ITRIP should be divided near the shunt resistor.

## 3. ITRIP Filter Capacitor

To prevent a malfunction, it is recommended to locate a ceramic capacitor near ITRIP pin. GND of the capacitor should be connected to Logic GND.

#### 4. Input Capacitor and Zener Diode

An input capaciter and a zener diode, a bootstrap capacitor should be located near the pin. It is recommended to select a low ESR capacitor such as a ceramic-type.

## I/O Equivalence Circuits

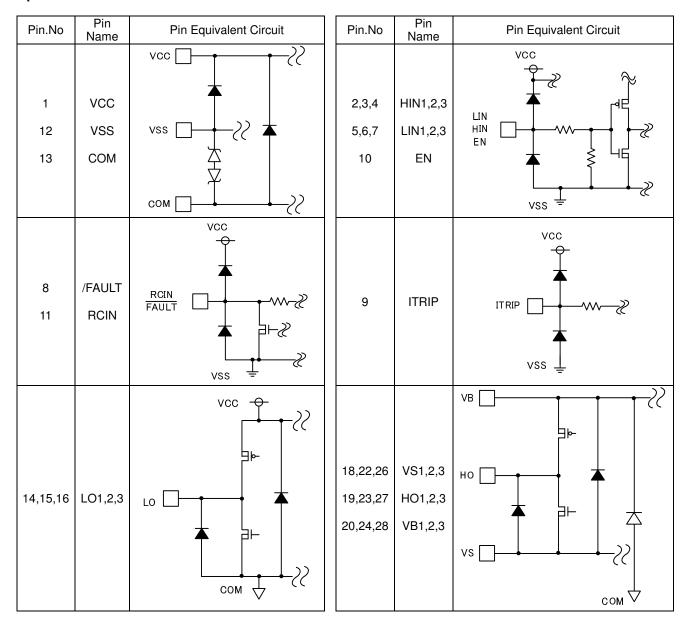


Figure 43. I/O Equivalent Circuits

#### **Operational Notes**

#### 1. Reverse Connection of Power Supply

Connecting the power supply in reverse polarity can damage the IC. Take precautions against reverse polarity when connecting the power supply, such as mounting an external diode between the power supply and the IC's power supply pins.

#### 2. Power Supply Lines

Design the PCB layout pattern to provide low impedance supply lines. Furthermore, connect a capacitor to ground at all power supply pins. Consider the effect of temperature and aging on the capacitance value when using electrolytic capacitors.

#### 3. Ground Voltage

Ensure that no pins are at a voltage below that of the ground pin at any time, even during transient condition.

#### 4. Ground Wiring Pattern

When using both small-signal and large-current ground traces, the two ground traces should be routed separately but connected to a single ground at the reference point of the application board to avoid fluctuations in the small-signal ground caused by large currents. Also ensure that the ground traces of external components do not cause variations on the ground voltage. The ground lines must be as short and thick as possible to reduce line impedance.

#### 5. Thermal Consideration

Should by any chance the power dissipation rating be exceeded the rise in temperature of the chip may result in deterioration of the properties of the chip. In case of exceeding this absolute maximum rating, increase the board size and copper area to prevent exceeding the Pd rating.

#### 6. Recommended Operating Conditions

These conditions represent a range within which the expected characteristics of the IC can be approximately obtained. The electrical characteristics are guaranteed under the conditions of each parameter.

#### 7. Inrush Current

When power is first supplied to the IC, it is possible that the internal logic may be unstable and inrush current may flow instantaneously due to the internal powering sequence and delays, especially if the IC has more than one power supply. Therefore, give special consideration to power coupling capacitance, power wiring, width of ground wiring, and routing of connections.

## 8. Operation Under Strong Electromagnetic Field

Operating the IC in the presence of a strong electromagnetic field may cause the IC to malfunction.

#### 9. Testing on Application Boards

When testing the IC on an application board, connecting a capacitor directly to a low-impedance output pin may subject the IC to stress. Always discharge capacitors completely after each process or step. The IC's power supply should always be turned off completely before connecting or removing it from the test setup during the inspection process. To prevent damage from static discharge, ground the IC during assembly and use similar precautions during transport and storage.

## 10. Inter-pin Short and Mounting Errors

Ensure that the direction and position are correct when mounting the IC on the PCB. Incorrect mounting may result in damaging the IC. Avoid nearby pins being shorted to each other especially to ground, power supply and output pin. Inter-pin shorts could be due to many reasons such as metal particles, water droplets (in very humid environment) and unintentional solder bridge deposited in between pins during assembly to name a few.

#### 11. Unused Input Pins

Input pins of an IC are often connected to the gate of a MOS transistor. The gate has extremely high impedance and extremely low capacitance. If left unconnected, the electric field from the outside can easily charge it. The small charge acquired in this way is enough to produce a significant effect on the conduction through the transistor and cause unexpected operation of the IC. So unless otherwise specified, unused input pins should be connected to the power supply or ground line.

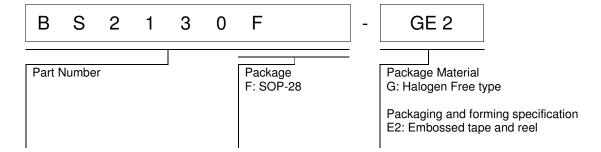
## 12. Ceramic Capacitor

When using a ceramic capacitor, determine the dielectric constant considering the change of capacitance with temperature and the decrease in nominal capacitance due to DC bias and others.

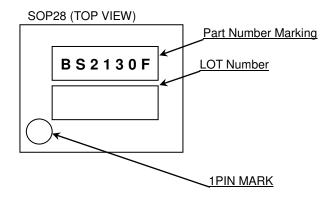
#### 13. Area of Safe Operation (ASO)

Operate the IC such that the output voltage, output current, and the maximum junction temperature rating are all within the Area of Safe Operation (ASO).

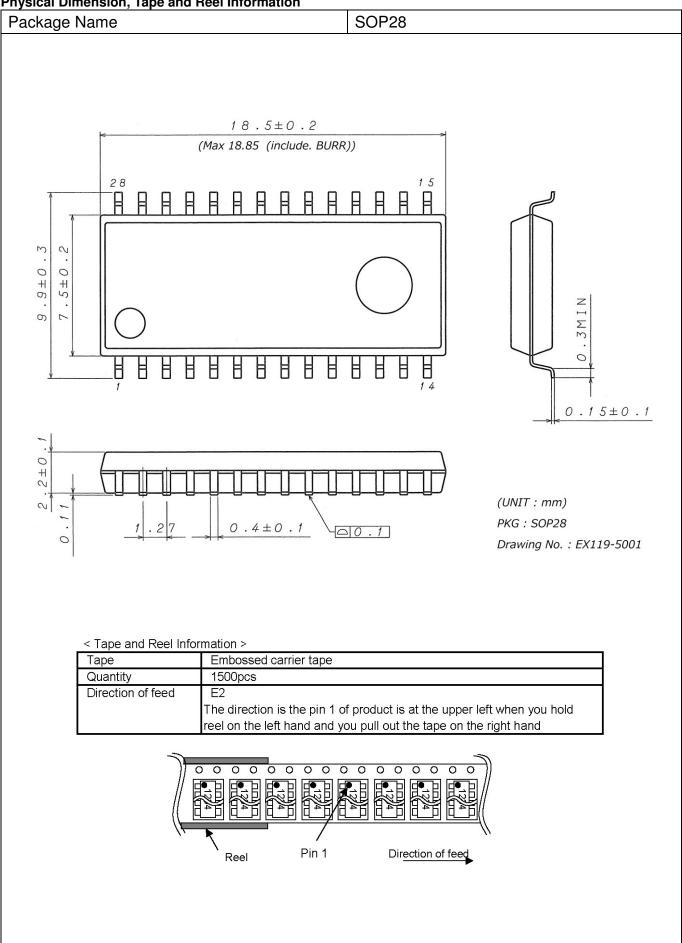
## **Ordering Information**



## **Marking Diagram**



Physical Dimension, Tape and Reel Information



## **Revision History**

Date	Revision	Changes
26.Feb.2016	001	New Release
31.May.2016	002	Addition P.21 Overshoot / Undershoot of Output Terminal Correction of errors P.4, P23
02.Feb.2017	003	Change of Absolute Maximum Ratings notation (Notation only. There is no change in rating)

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JAPAN	USA	EU	CHINA
CLASSⅢ	CLASSⅢ	CLASS II b	CLASSIII
CLASSIV		CLASSⅢ	

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  - [d] Use of our Products in places where the Products are exposed to static electricity or electromagnetic waves
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# BS2130F-G - Web Page

**Distribution Inventory** 

Part Number	BS2130F-G
Package	SOP-28
Unit Quantity	1500
Minimum Package Quantity	1500
Packing Type	Taping
Constitution Materials List	inquiry
RoHS	Yes

单击下面可查看定价,库存,交付和生命周期等信息

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